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| Notice of References Cited | Application/Control No. 10/709,015 | Applicant(s)/Patent Under Reexamination BANET ET AL. | |
| | Examiner Patricia C. Mallari | Art Unit 3736 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-6,533,729 B1 | 03-2003 | Khair et al. | 600/503 |
| | B | US-6,814,705 B2 | 11-2004 | Kawaguchi, Keizoh | 600/500 |
| | C | US-6,700,174 | 03-2004 | Miu et al. | 257/419 |
| | D | US-5,237,997 A | 08-1993 | Greubel et al. | 600/485 |
| | E | US-5,752,920 | 05-1998 | Ogura et al. | 600/494 |
| | F | US-6,618,603 B2 | 09-2003 | Varalli et al. | 600/345 |
| | G | US-6,468,222 B1 | 10-2002 | Mault et al. | 600/531 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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